# 2SK3372G

### Silicon N-Channel Junction FET

For impedance conversion in low frequency For electret capacitor microphone

#### Features

- $\bullet$  High mutual conductance  $g_{m}$
- Low noise voltage NV

#### Package

- Code
- SSSMini3-F2 • Pin Name
  - 1: Drain
  - 2: Source
  - 3: Gate

Absolute	Maximum	Ratings	$T_{o} = 25^{\circ}C$	

Parameter	Symbol	Rating	Unit	
Drain-source voltage (Gate open)	V <sub>DSO</sub>	20	V	
Gate-drain voltage (Source open)	V <sub>GDO</sub>	20	V	
Drain-source current (Gate open)	I <sub>DSO</sub>	2	mA	
Gate-drain current (Source open)	I <sub>GDO</sub>	2	mA	
Gate-source current (Drain open)	I <sub>GSO</sub>	2	mA	
Power dissipation	P <sub>D</sub>	100	mW	
Operating ambient temperature	T <sub>opr</sub>	-20 to +80	°C	
Storage temperature	T <sub>stg</sub>	-55 to +125	°C	

Marking Symbol: 1H

#### Electrical Characteristics $T_a = 25^{\circ}C \pm 3^{\circ}C$

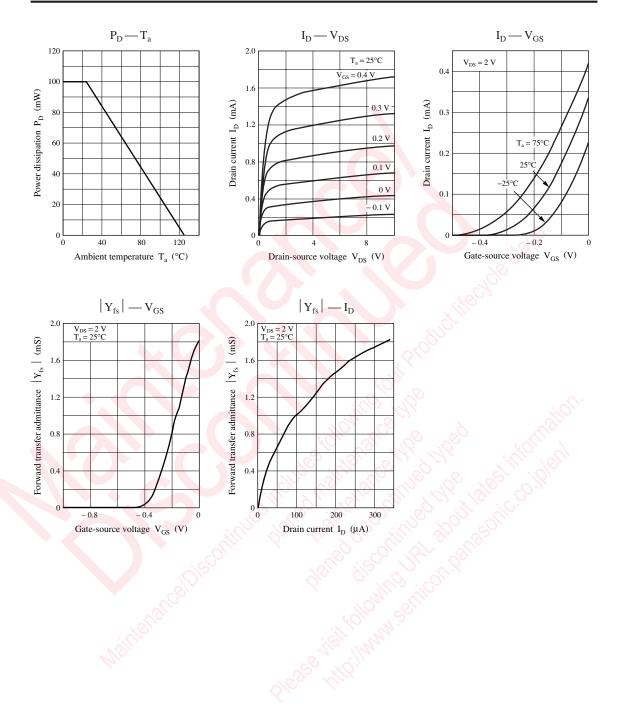
Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Drain current *1	ID	$V_{\rm DS} = 2.0 \text{ V}, R_{\rm D} = 2.2 \text{ k}\Omega \pm 1\%$	100	-011	470	μΑ
Drain-source current	I <sub>DSS</sub>	$V_{DS} = 2.0 \text{ V}, R_D = 2.2 \text{ k}\Omega \pm 1\%, V_{GS} = 0$	107	2	460	μΑ
Mutual conductance	gm	$V_D = 2.0 V, V_{GS} = 0, f = 1 kHz$	660	1 600		μS
Noise voltage	♡ NV	$V_D = 2.0 V, R_D = 2.2 k\Omega \pm 1\%$ $C_O = 5 pF, A-Curve$	<u> </u>		4	μV
Voltage gain	G <sub>V1</sub>	$V_D = 2.0 V, R_D = 2.2 k\Omega \pm 1\%$ $C_O = 5 pF, e_G = 10 mV, f = 1 kHz$	-7.5	-4.7		dB
	G <sub>V2</sub>	$V_D = 12 V, R_D = 2.2 k\Omega \pm 1\%$ $C_O = 5 pF, e_G = 10 mV, f = 1 kHz$	-4.0	-1.5		
	G <sub>V3</sub>	$V_D = 1.5 V, R_D = 2.2 k\Omega \pm 1\%$ $C_O = 5 pF, e_G = 10 mV, f = 1 kHz$	-8.0	-5.0		
	$\Delta  G_{V}.f ^{*2}$	$V_D = 2.0 \text{ V}, R_D = 2.2 \text{ k}\Omega \pm 1\%$ $C_O = 5 \text{ pF}, e_G = 10 \text{ mV}, f = 1 \text{ kHz to } 70 \text{ Hz}$		0	1.7	
Voltage gain difference	$ G_{V2} - G_{V1} $		0		4.0	dB
	G <sub>V1</sub> - G <sub>V3</sub>		0		1.7	

Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

2. \*1:  $I_{\text{D}}$  is assured for  $I_{\text{DSS}}.$ 

\*2:  $\Delta$  | G<sub>V</sub>. f | is assured for AQL 0.065%. (The measurement method is used by source-grounded circuit.)

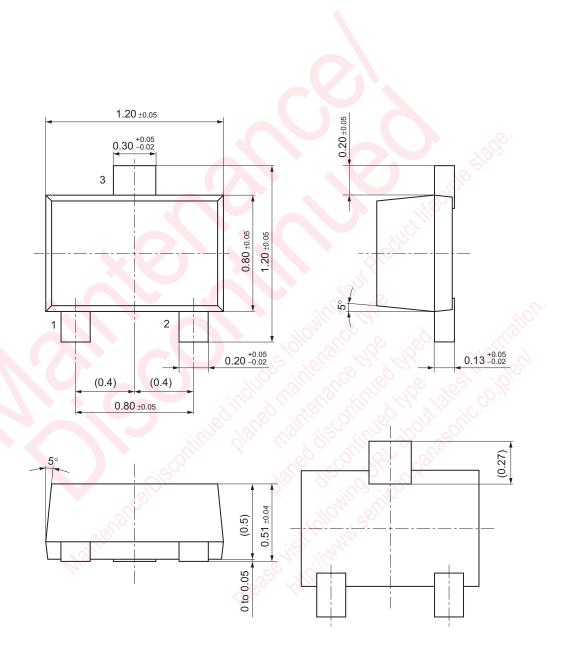
### Panasonic



### Panasonic

### SSSMini3-F2

Unit: mm



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